	Reg. No. :											
Question Paper Code: 56403												
B.E. / B.Tech. DEGREE EXAMINATION, DEC 2020												
Sixth Semester												
Electronics and Communication Engineering												
15UEC603- VLSI DESIGN												
(Regulation 2015)												
Duration: 1.15 hrs							laximum: 30 Marks					
PART A - $(6 \times 1 = 6 \text{ Marks})$												
(Answer any six of the following questions)												
1.	In continuous assignment left hand sid	le must b	e								CC)1-R
	(a) Net (b) Reg (c) Scalar	or v	ector	net		(d)	Scala	ar or	vecto	or re	g
2. The primary mechanisms for modeling the behavior of a Verilog design needs									CO	1- R		
(a) Initial statement (b) Always statement (c) Both (a) and (b) (d) Only (nly (a)	
3.	CMOS technology is used in developing								CC)2-U		
	(a) Microprocessors (b) Micro	conti	rolle	rs							
	(c) Digital logic circuits (d) all of	the n	nenti	oned							
4.	In CMOS fabrication, the photoresist l	layer is e	xpos	ed to)						CO	2- R
	(a) visible light (b) infra red light	(c) ul	travi	olet	light		(d)	fluor	escei	nt		
5.	In CMOS circuits, which type of p switching of transient current and c capacitance?	oower di charging	ssipa & c	tion lisch	occi argin	urs (ng o	due f loa	to ad			CO	3-U
	(a) Static dissipation	(b)Dyna	mic c	lissip	oatio	n						
	(c) Both a and b	(d) None	e of tl	ne ab	ove							
6.	The number of pass transistors connected in series can be increased if								CO3	3- R		
	(a) Compressor is connected (b) Ground is connected											
	(c) Voltage regulator is connected		(d)]	Buff	er is	conr	necte	d				

7.	Charge leakage and adding	noise margin proble	ems can be addressed by		CO4-U					
	(a) Keeper circuit	(b) domino gate	(c) pass transistor (c	l) transmissi	on gate					
8.	In CMOS NAND gat	CO4- R								
	(a) Series	(b) Parallel	(c) Cascade (d	l) Random						
9.	The number of test ve		CO5-A							
	(a) $2^{(m+n)}$	(b) $2^{((m+n)/2)}$	(c) $2^{(m-n)}$	(d) $2^{2(m+n)}$						
10.	The process of removi		CO5- R							
	(a) Equivalent removi	ng	(b) Fault collapsing							
	(c) Fault reduction		(d) Bulk damaging							
	PART – B (3 x 8= 24 Marks)									
	(Answer any three of the following questions)									
11.	Write a Verilog progr behavioral modeling.	CO1-U	(8)							
12.	Explain in detail DC t	CO2-U	(8)							
13.	Analyze the static and dynamic power dissipation in CMOS circuits with necessary diagrams and expressions.				(8)					
14.	Discuss the compariso	on of circuit families		CO4 -U	(8)					
15.	Describe the scan bas testability in detail.	ed approaches and bui	lt in self-test to design for	CO5- U	(8)					